

ROUND TYPE LED LAMPS



L8SR2040-PF

DATA SHEET

DOC. NO: QW0905-L8SR2040-PF

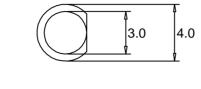
REV. : <u>A</u>

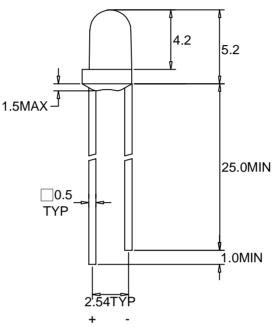
DATE : 25 - May. - 2009



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Package Dimensions

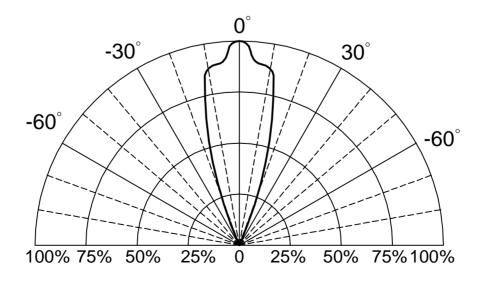




Note: 1.All dimension are in millimeter tolerance is ± 0.25 mm unless otherwise noted.

2. Specifications are subject to change without notice.

Directivity Radiation





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Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings	UNIT
Parameter		Red	UNII
Forward Current	lF	15	mA
Peak Forward Current Duty 1/10@10KHz	lfp	70	mA
Power Dissipation	PD	50	mW
Reverse Current @5V	lr	10	μ A
Operating Temperature	Topr	-40 ~ +85	$^{\circ}\!\mathbb{C}$
Storage Temperature	Tstg	-40 ~ +100	$^{\circ}$ C

Typical Electrical & Optical Characteristics (Ta=25 °C)

PART NO MATERIAL		COLOR		Peak wave length λ Pnm	Spectral halfwidth $\triangle \lambda$ nm	Forward voltage @10mA(V)		Luminous intensity @10mA(mcd)		Viewing angle 2 θ 1/2 (deg)
		Emitted	Lens			Min.	Тур.	Min.	Тур.	
L8SR2040-PF	GaAlAs	Red	Red Diffused	660	20	1.5	2.1	20	45	36

Note : 1.The forward voltage data did not including $\pm 0.1 V$ testing tolerance.

2. The luminous intensity data did not including $\pm 15\%$ testing tolerance.



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Typical Electro-Optical Characteristics Curve

8SR CHIP

Fig.1 Forward current vs. Forward Voltage

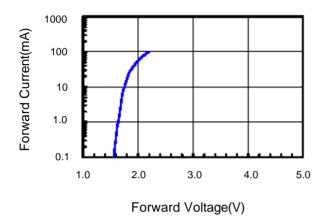
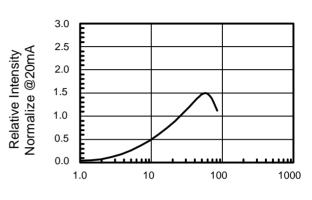


Fig.2 Relative Intensity vs. Forward Current



Forward Current(mA)

Fig.3 Forward Voltage vs. Temperature

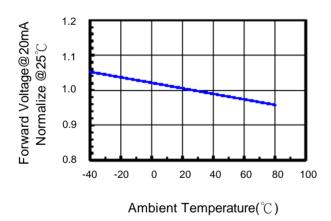


Fig.4 Relative Intensity vs. Temperature

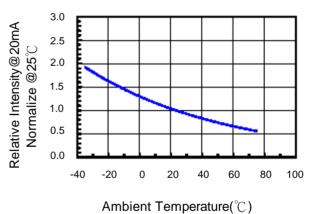
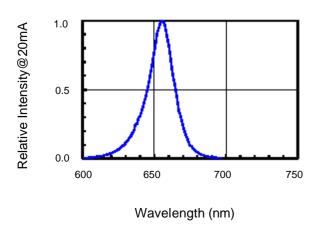


Fig.5 Relative Intensity vs. Wavelength





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Soldering Condition(Pb-Free)

1.Iron:

Soldering Iron:30W Max Temperature 350°C Max

Soldering Time: 3 Seconds Max(One time only)
Distance: 2mm Min(From solder joint to body)

2. Wave Soldering Profile

Dip Soldering

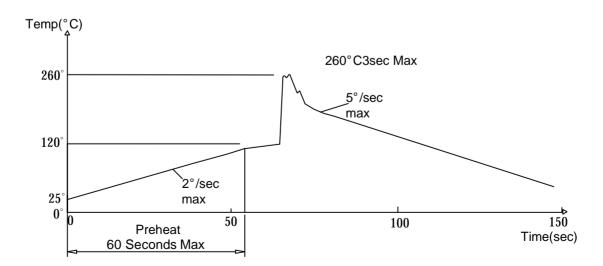
Preheat: 120°C Max

Preheat time: 60seconds Max

Ramp-up 2° C/sec(max)

Ramp-Down:-5° C/sec(max) Solder Bath:260° C Max Dipping Time:3 seconds Max

Distance:2mm Min(From solder joint to body)



Note: 1. Wave solder should not be made more than one time.

2. You can just only select one of the soldering conditions as above.



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Reliability Test:

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in electrical and themal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 ℃±5℃ 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 °C±5 °C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 °C ±5 °C 2.RH=90 %~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hours.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 °C±5 °C &-40 °C±5 °C (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 °C ±5 °C 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 °C ±5 °C 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2